

**INFORMATION DISCLOSURE
CITATION**

ATTY. DOCKET NO.

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APPLICANT

BOURRET, et al.

FILING DATE

December 13, 2005

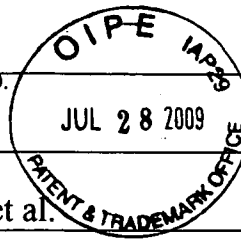
SERIAL NO.

10/560,448

GROUP

2621

(Use several sheets if necessary)


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*Examiner

/Trang Tran/

Date Considered

10/26/2009

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Initial a copy of this form with next communication to applicant.